

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

Appl. No.: 10/771,628



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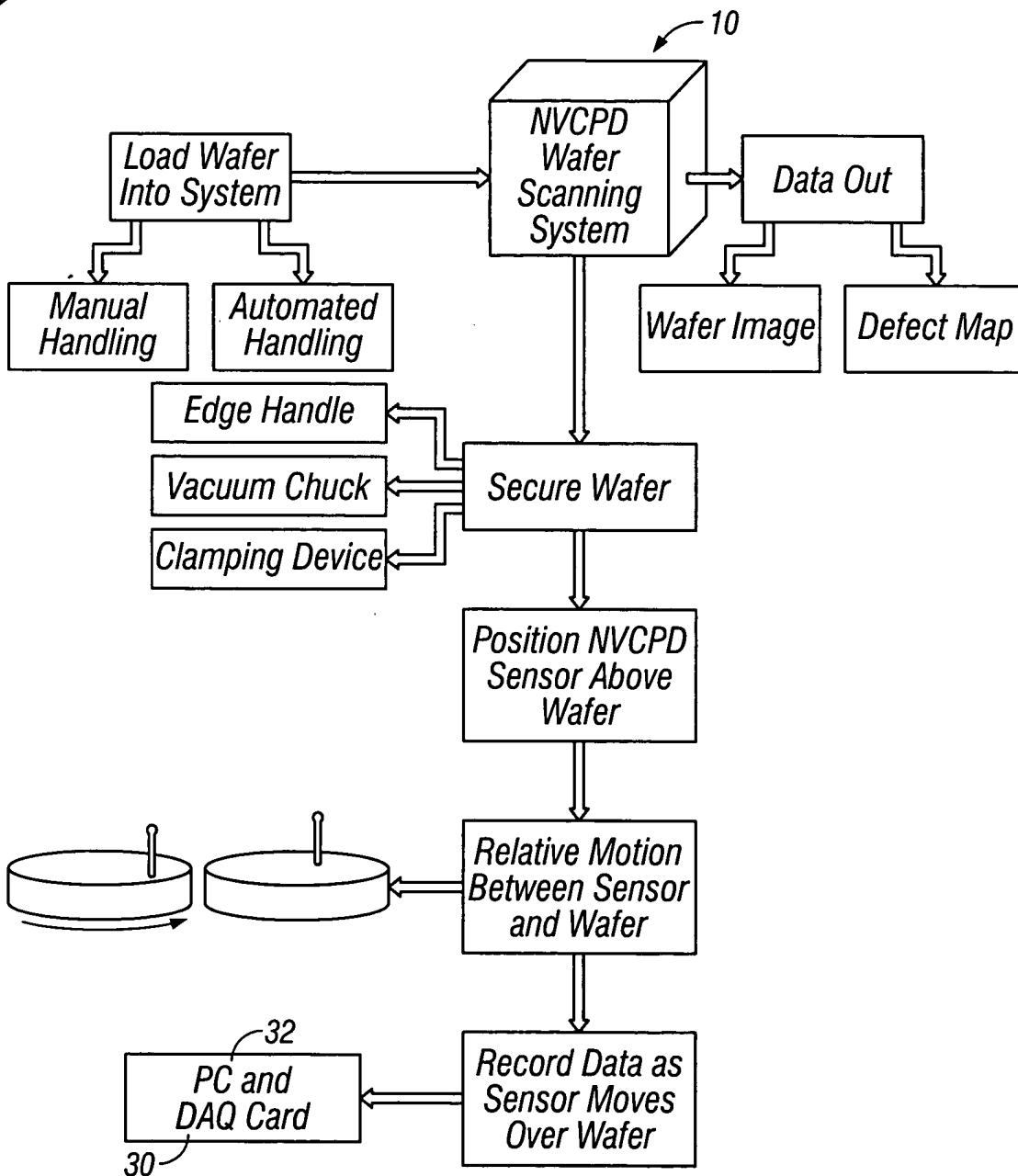


FIG. 1

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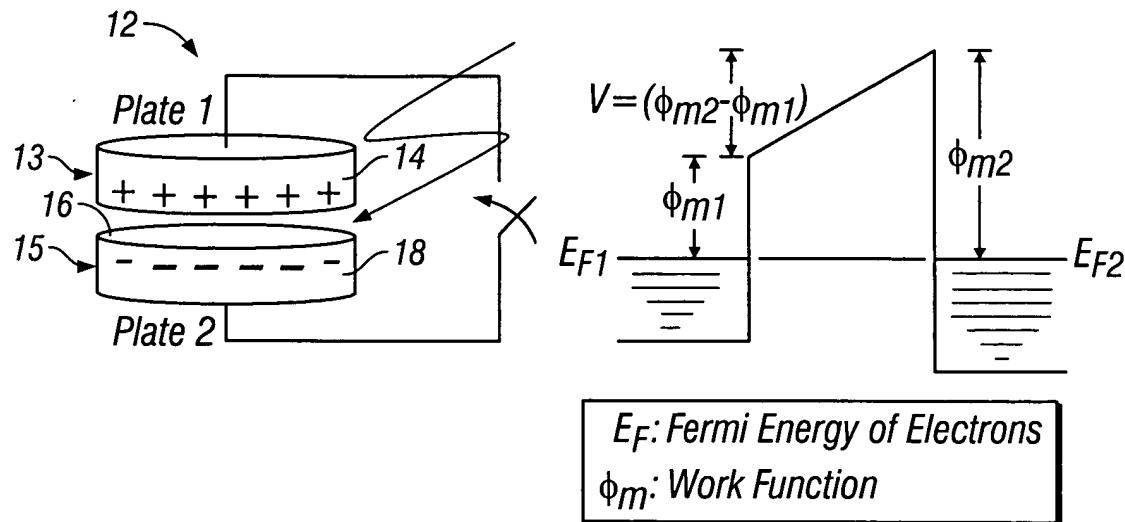


FIG. 2

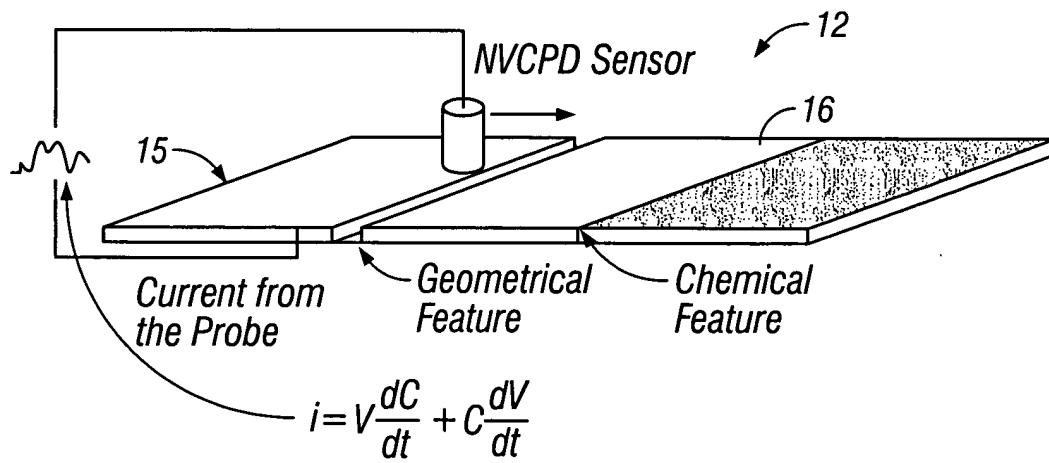


FIG. 3

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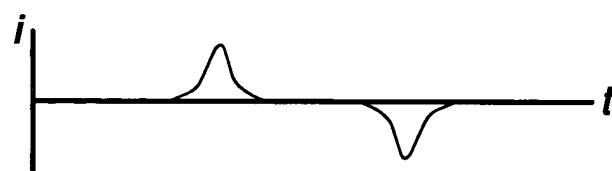
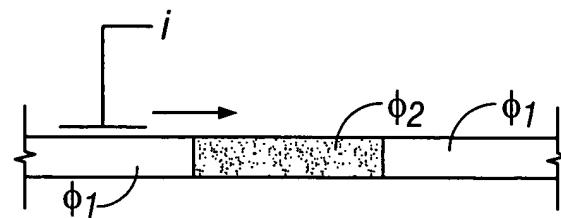


FIG. 4

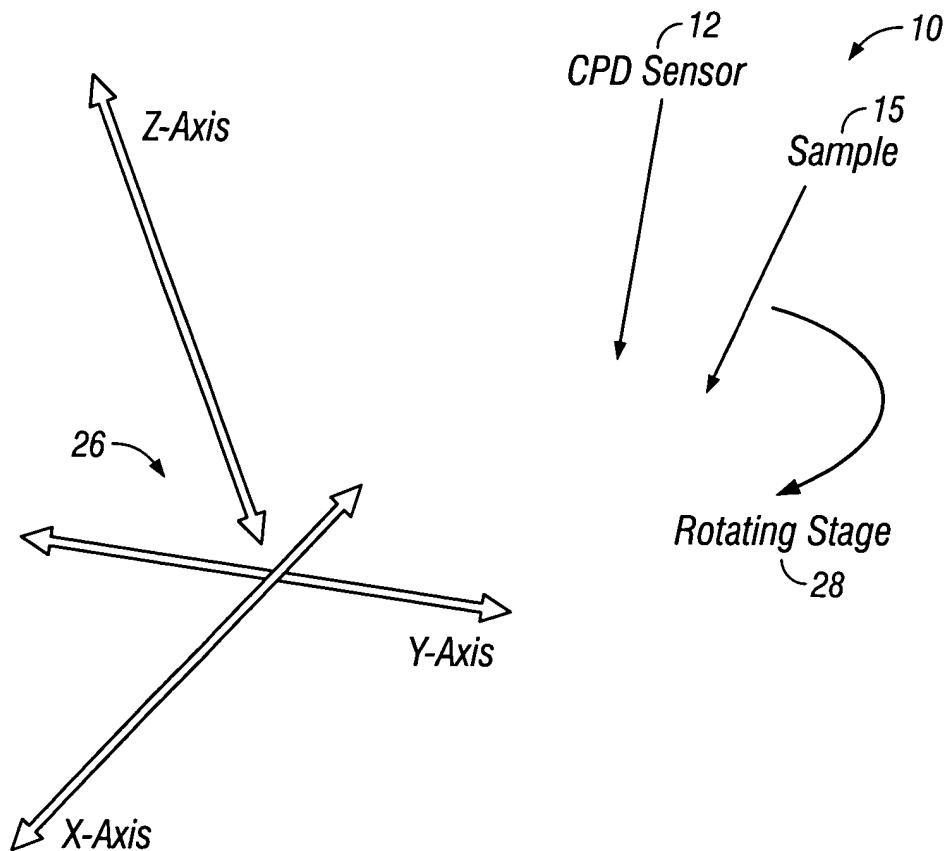
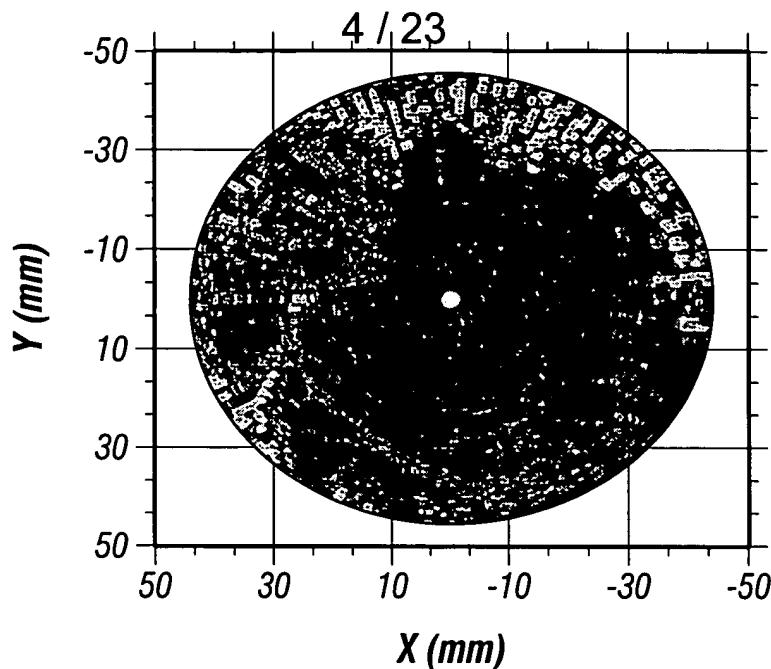


FIG. 5

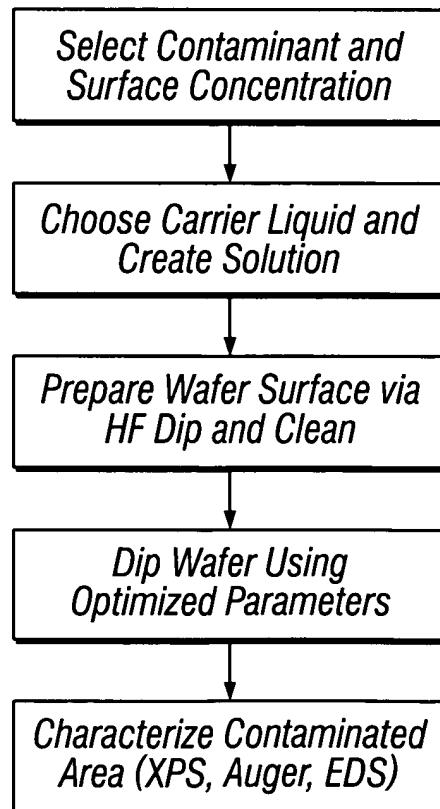
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**FIG. 6**



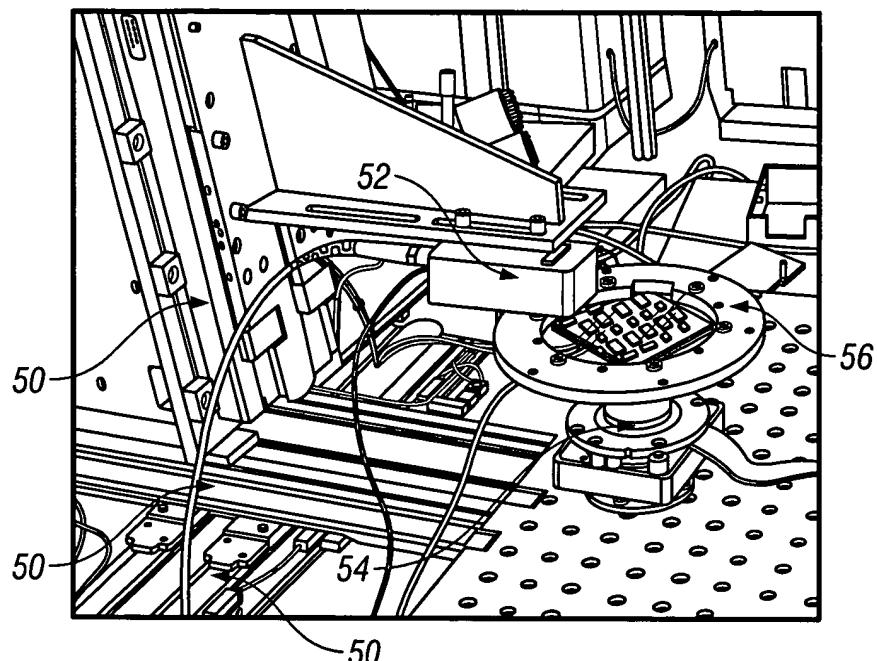
**FIG. 7**

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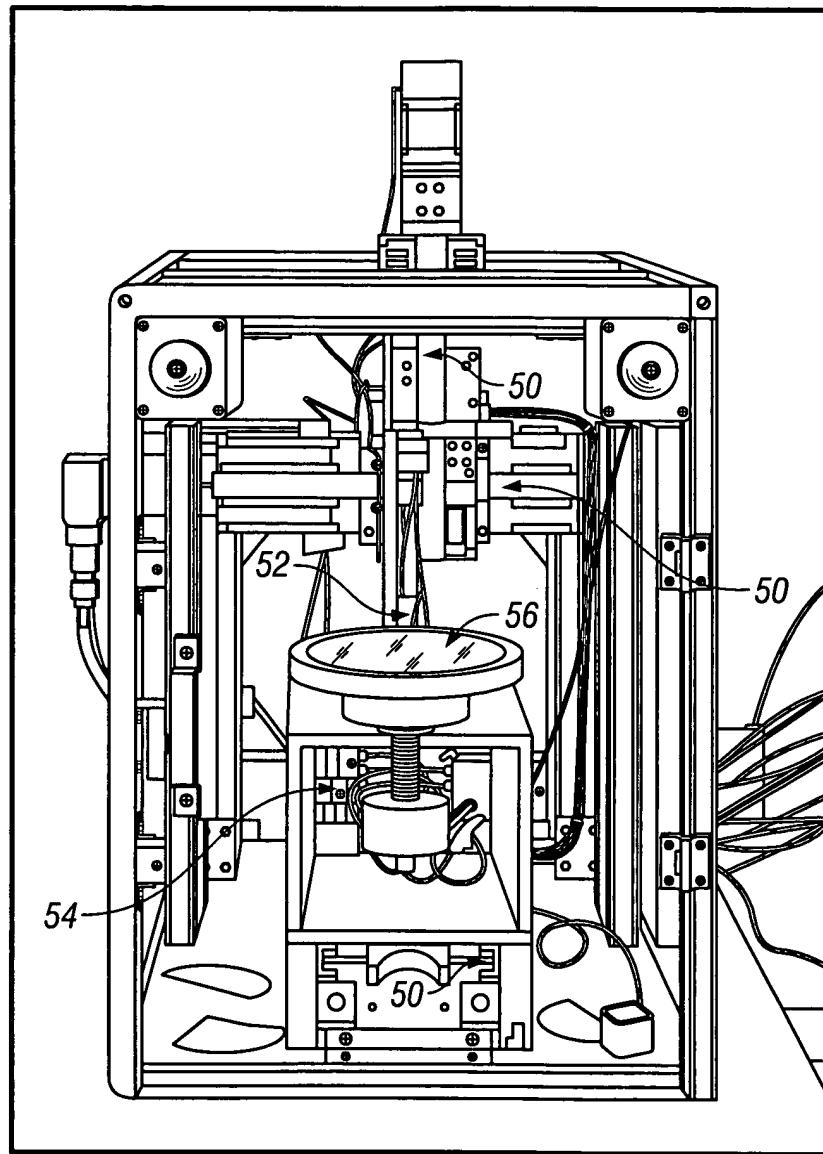
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**FIG. 8A**

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**FIG. 8B**

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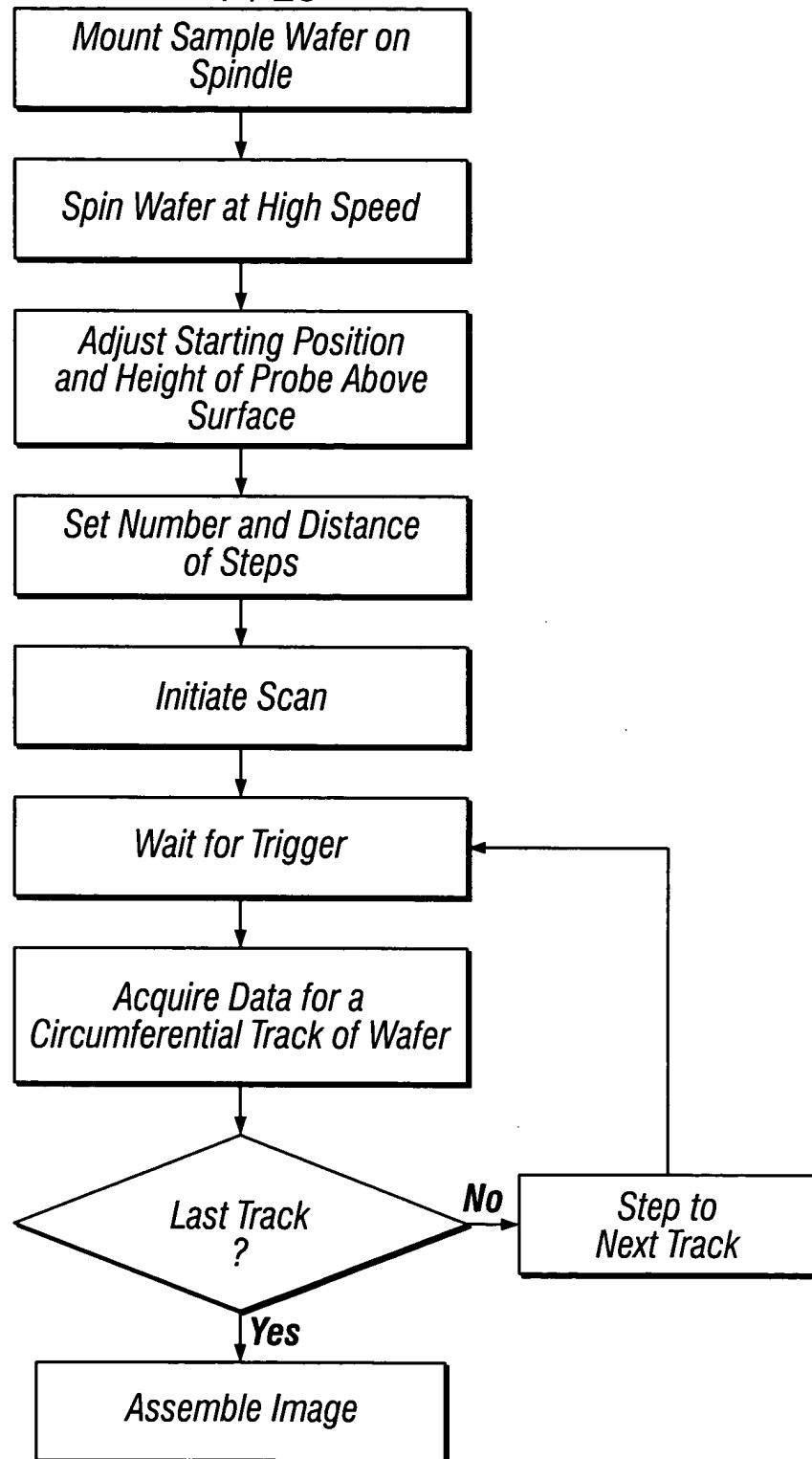


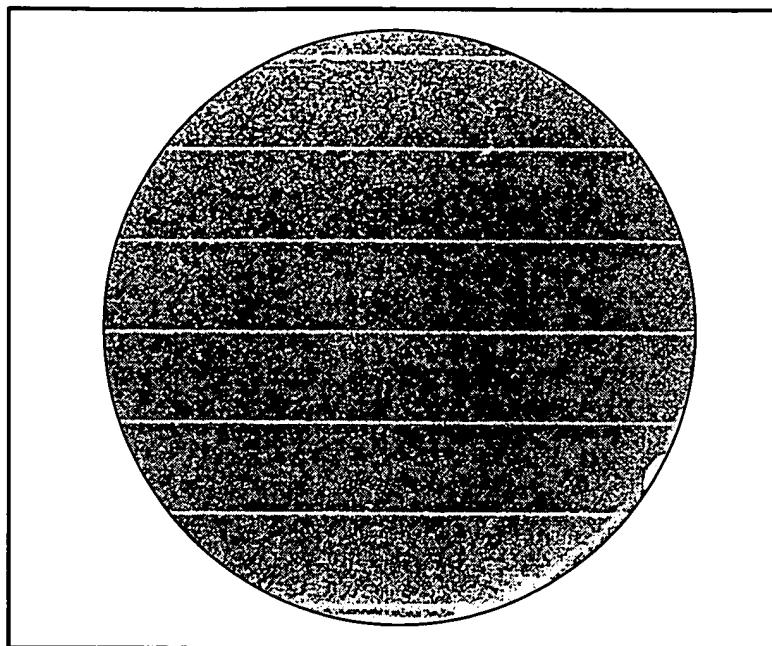
FIG. 9

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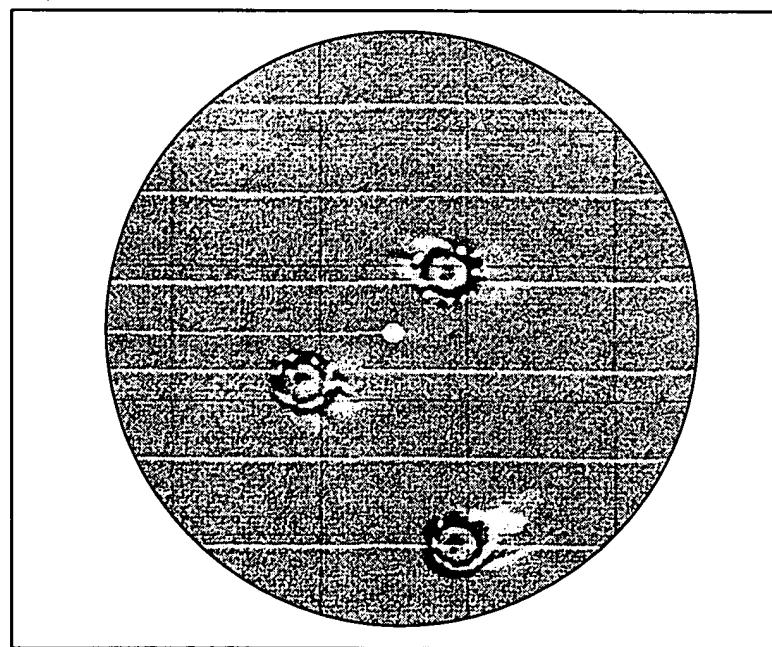
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**FIG. 10A**



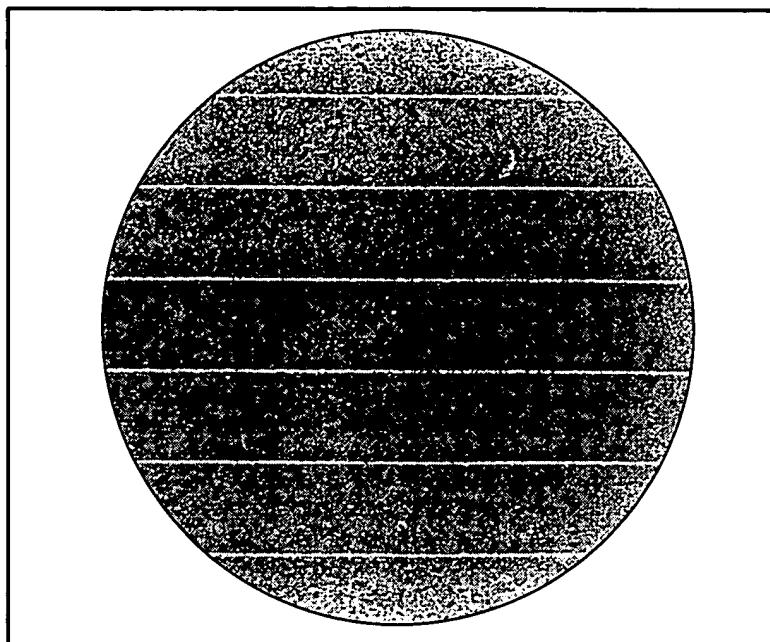
**FIG. 10B**

Title: WAFER INSPECTION SYSTEM

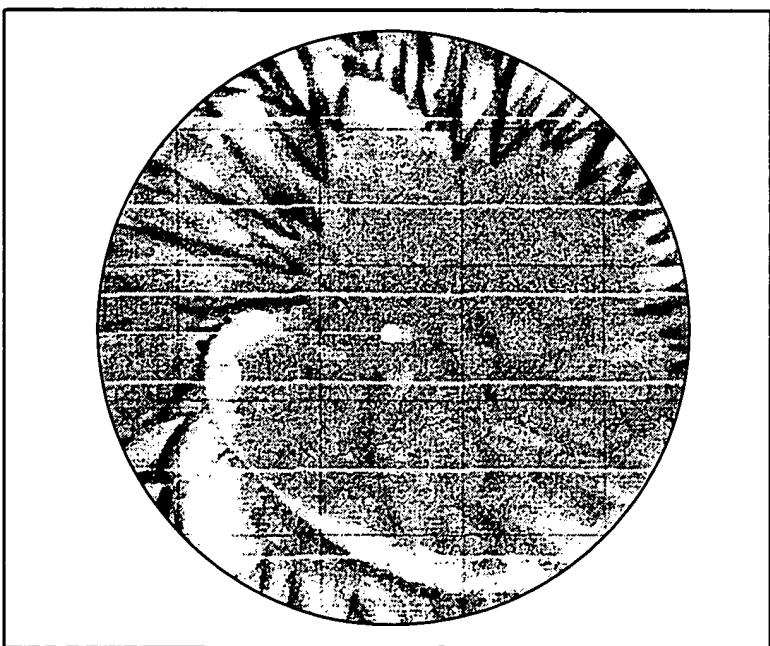
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**FIG. 11A**



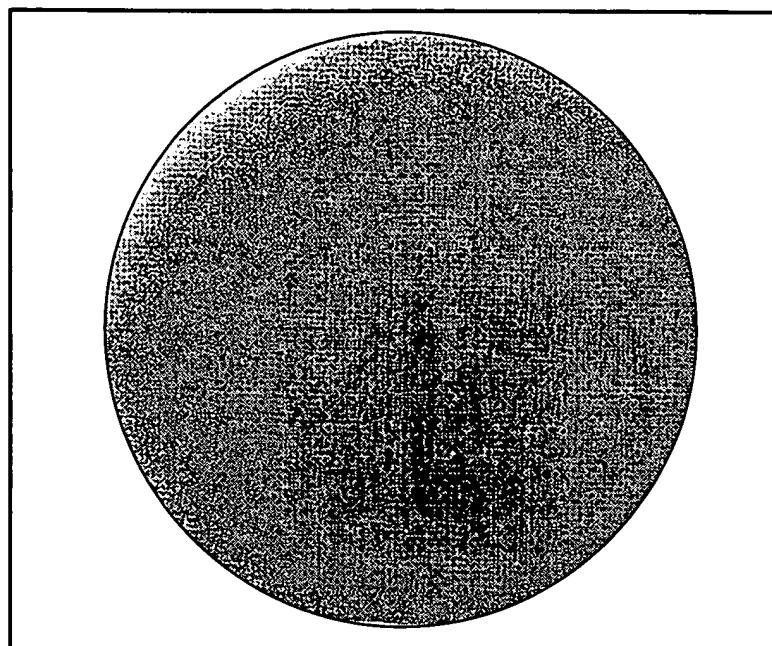
**FIG. 11B**

Title: WAFER INSPECTION SYSTEM

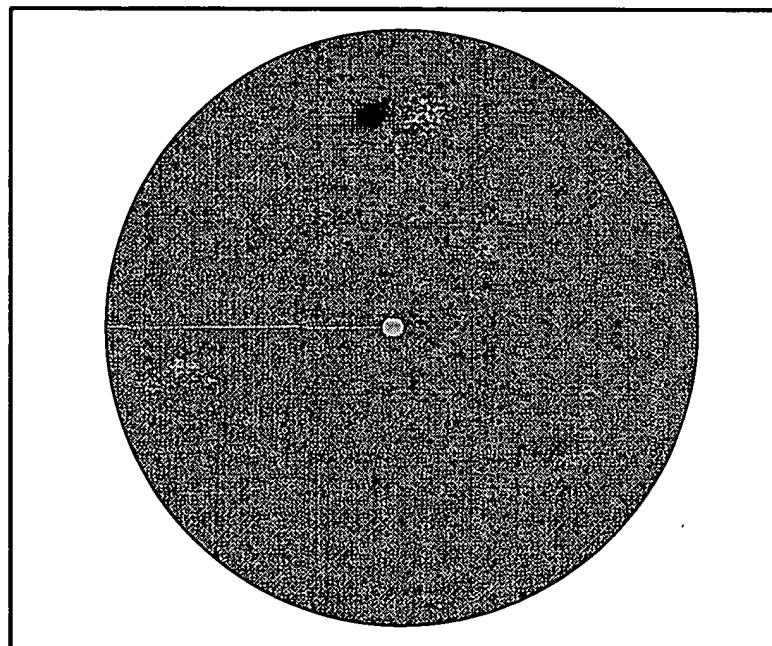
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**FIG. 12A**



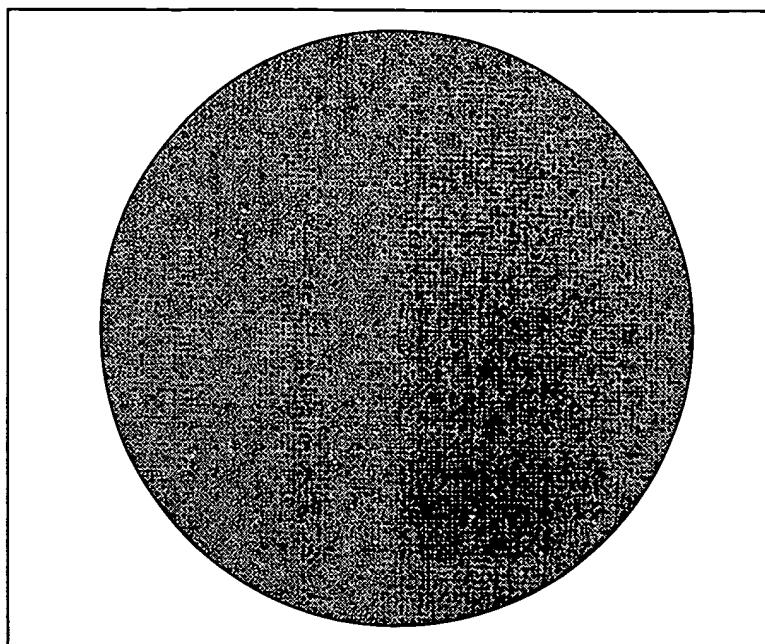
**FIG. 12B**

Title: WAFER INSPECTION SYSTEM

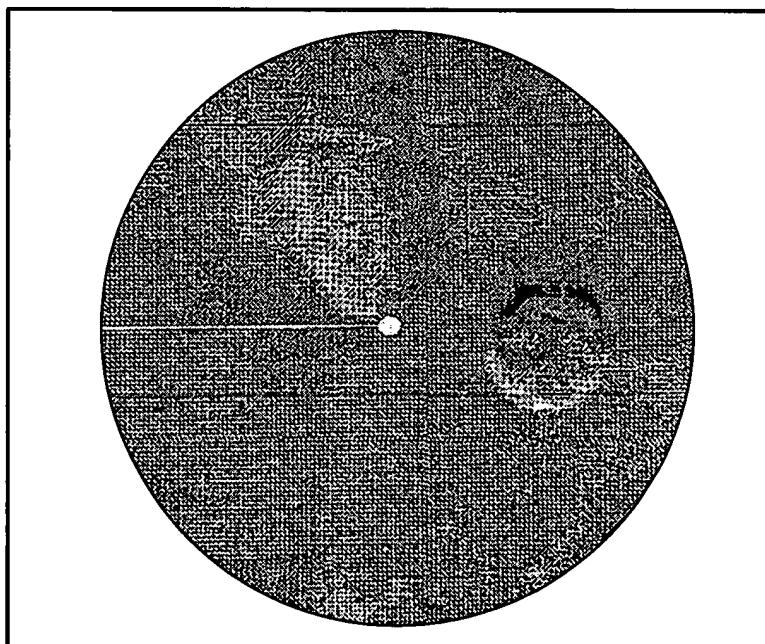
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**FIG. 13A**



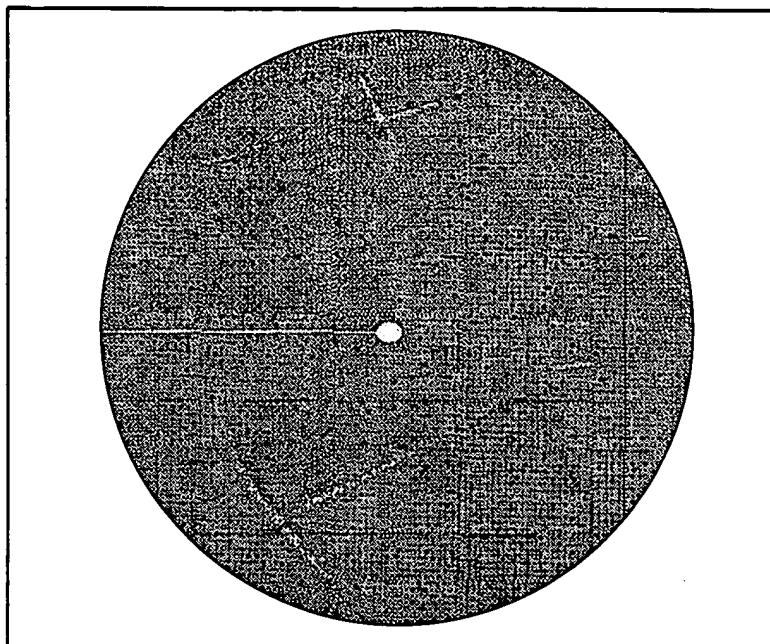
**FIG. 13B**

Title: WAFER INSPECTION SYSTEM

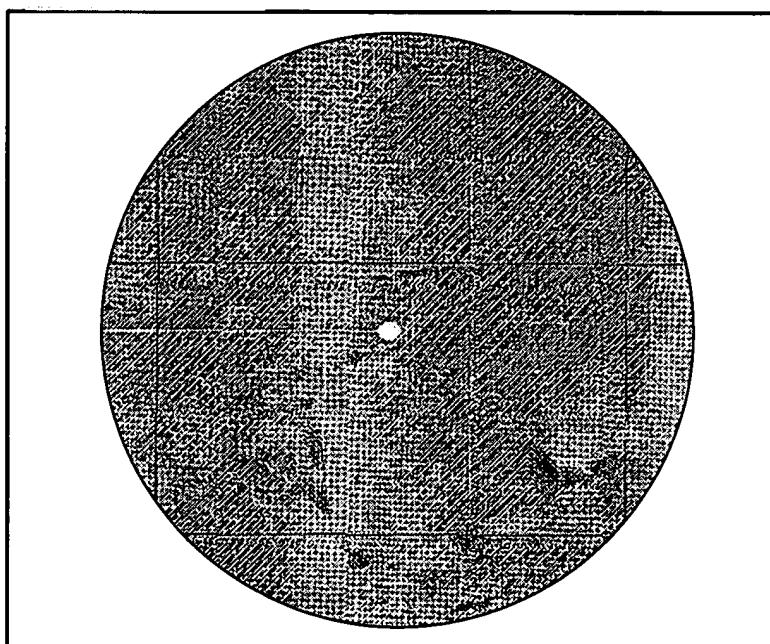
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*FIG. 14*



*FIG. 15*

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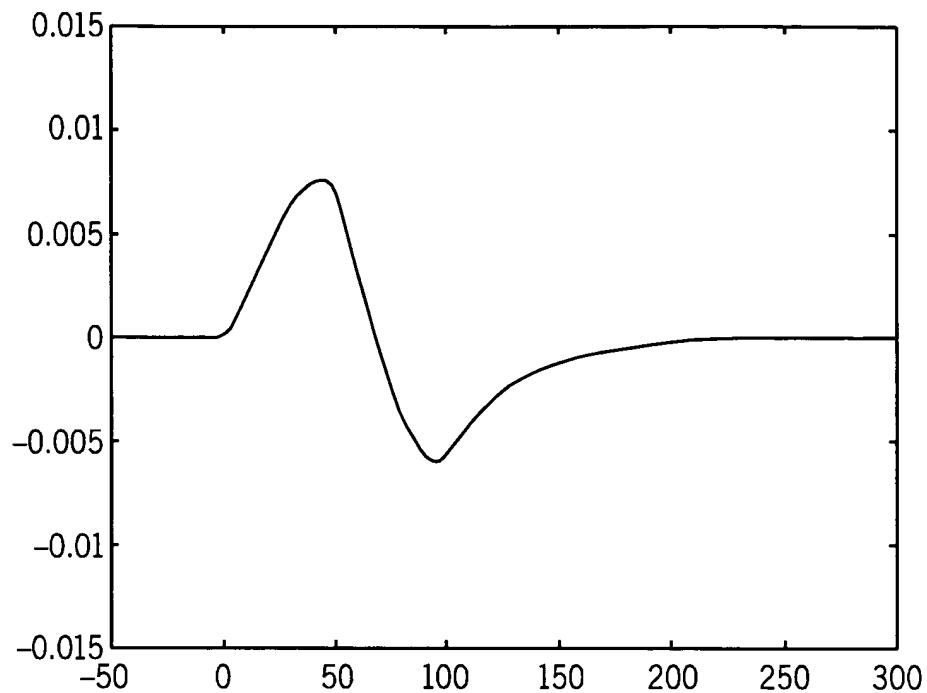


FIG. 16

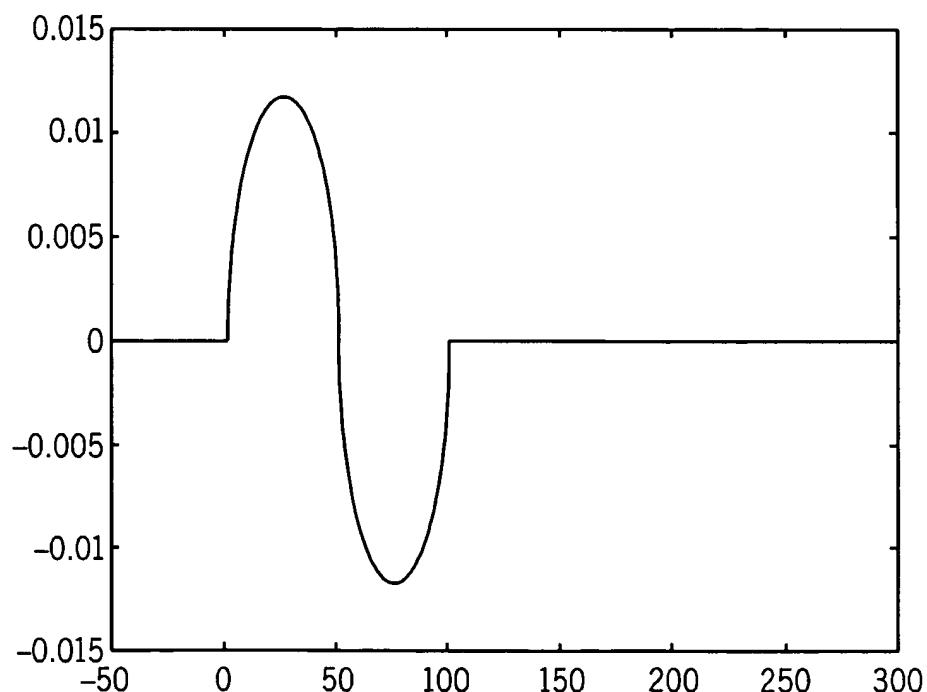


FIG. 17

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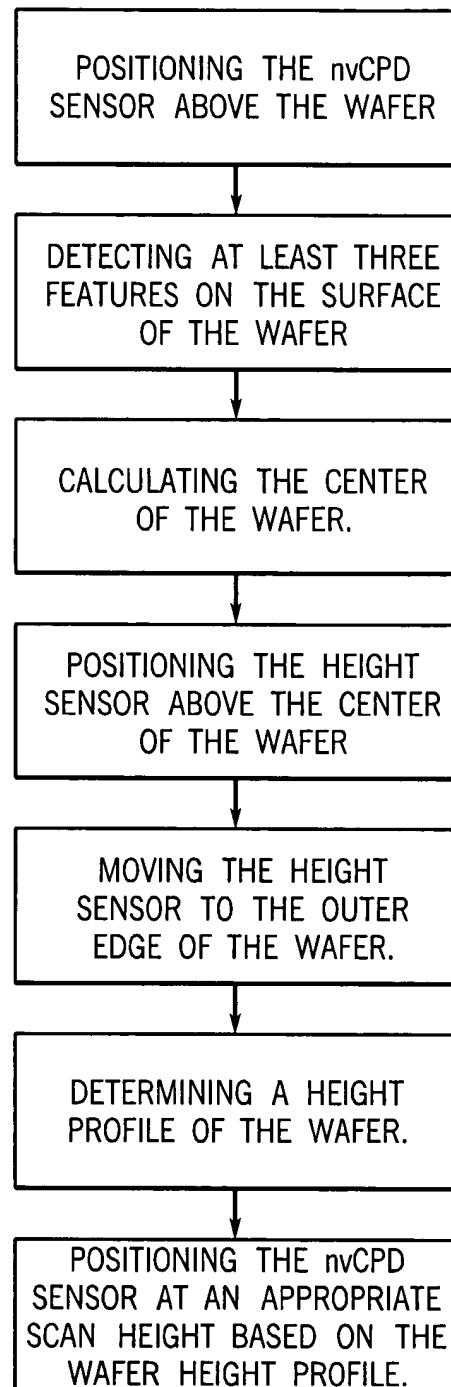


FIG. 18

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FIG. 19

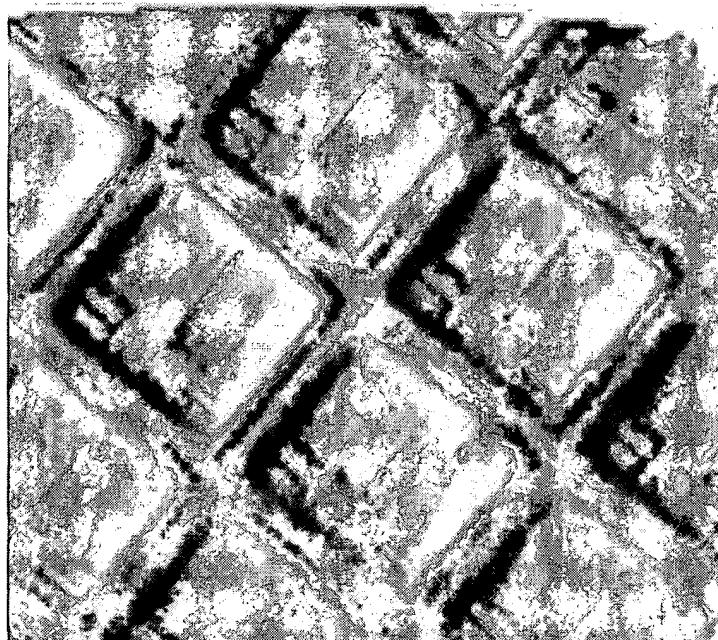


FIG. 20

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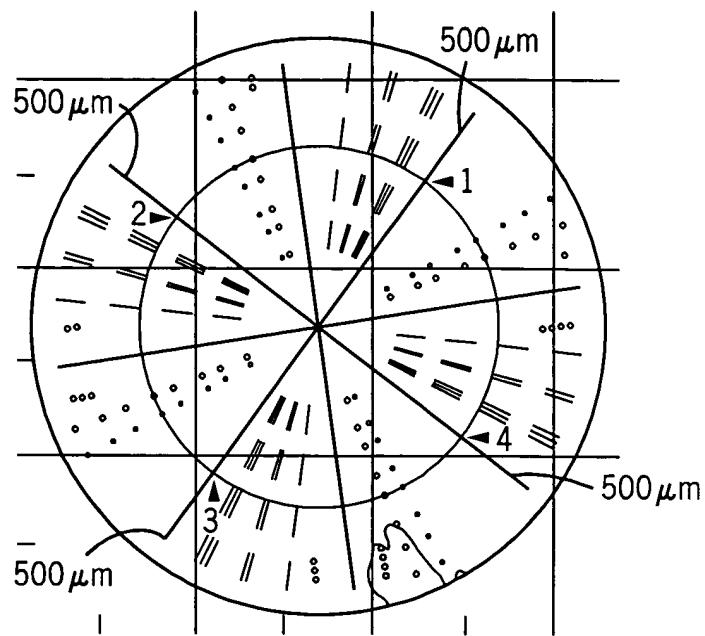


FIG. 21A

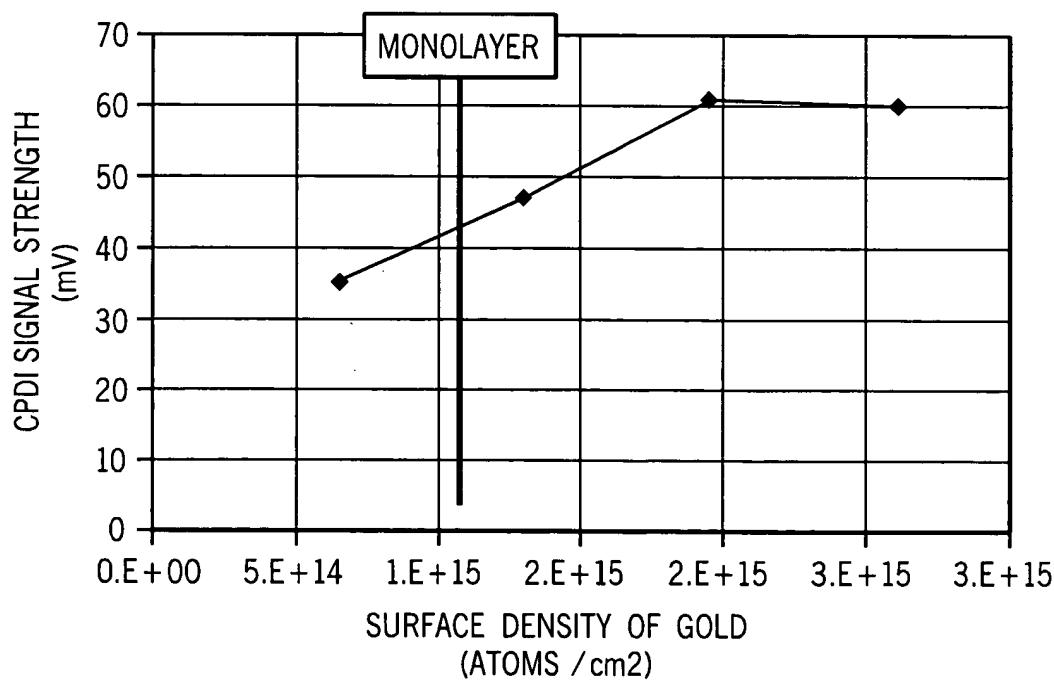


FIG. 21C

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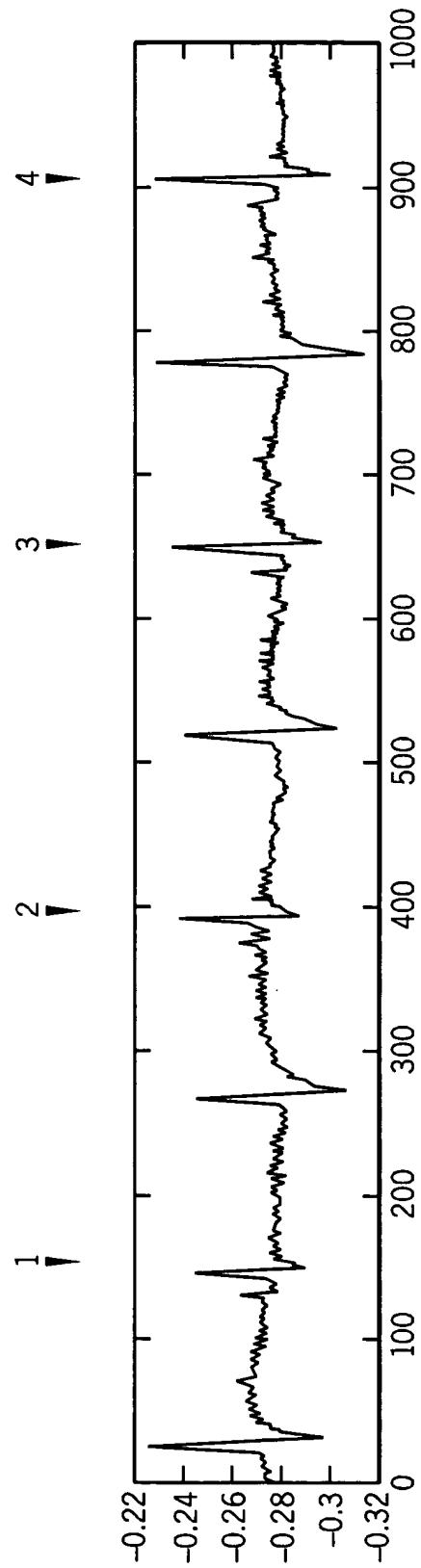


FIG. 21B

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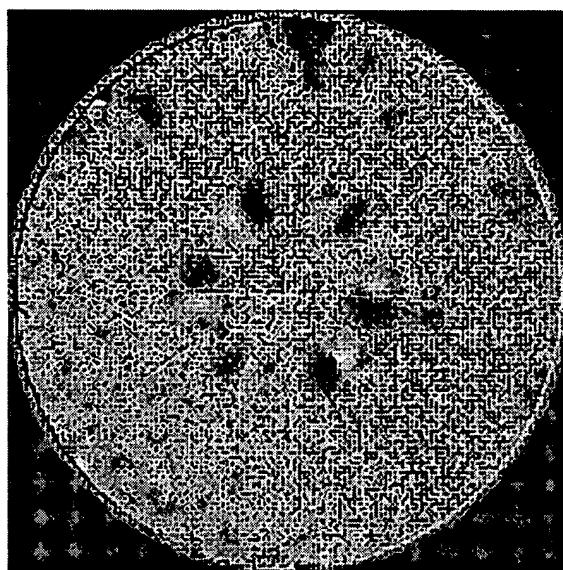


FIG. 22A

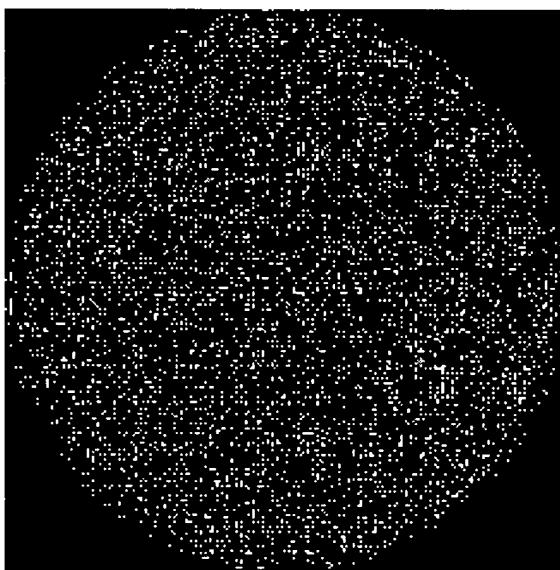


FIG. 22B

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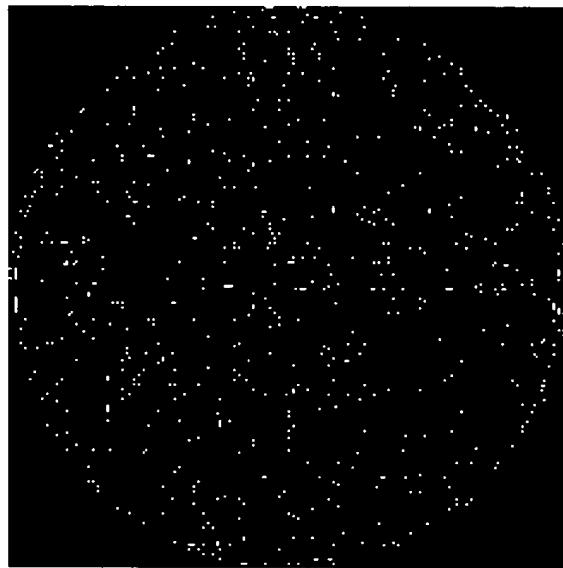


FIG. 22C

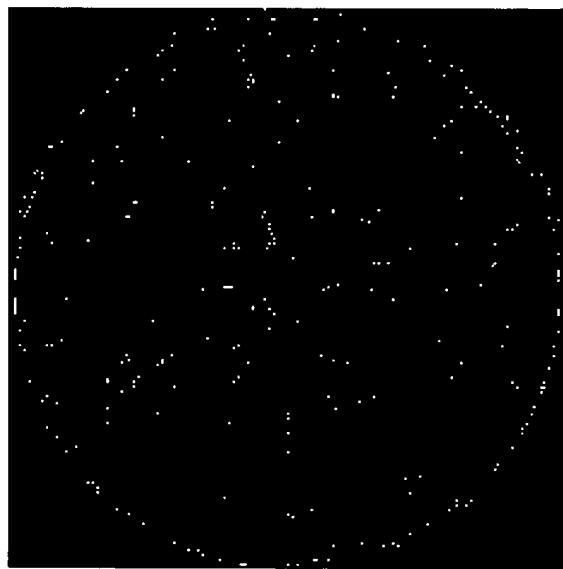


FIG. 22D

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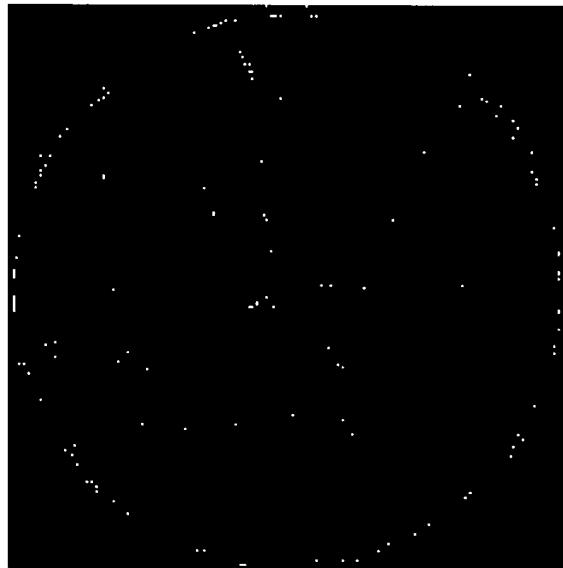


FIG. 22E

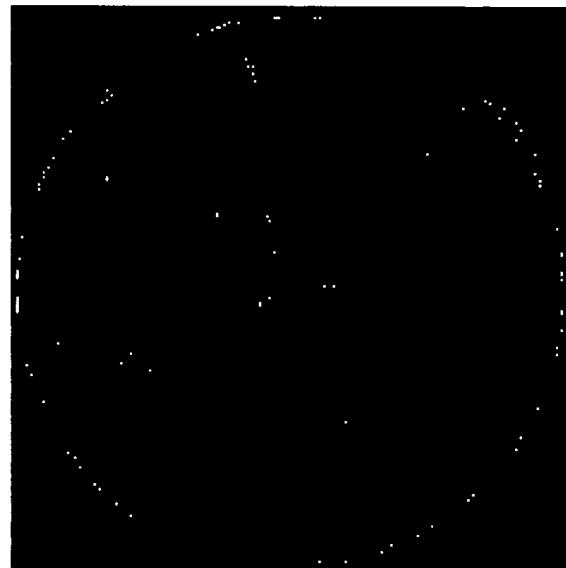


FIG. 22F

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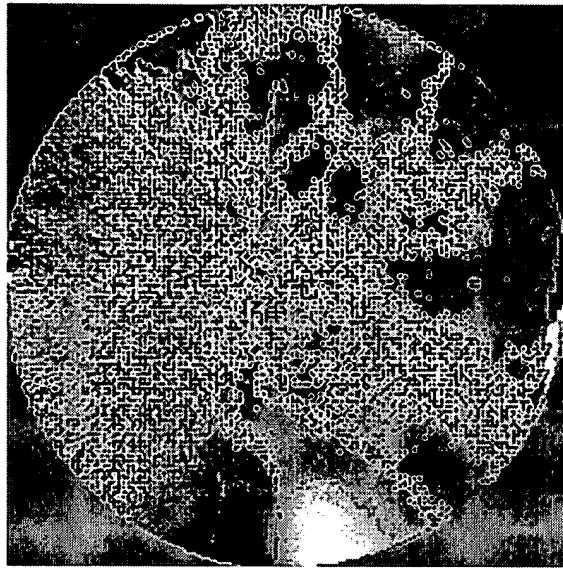


FIG. 23A

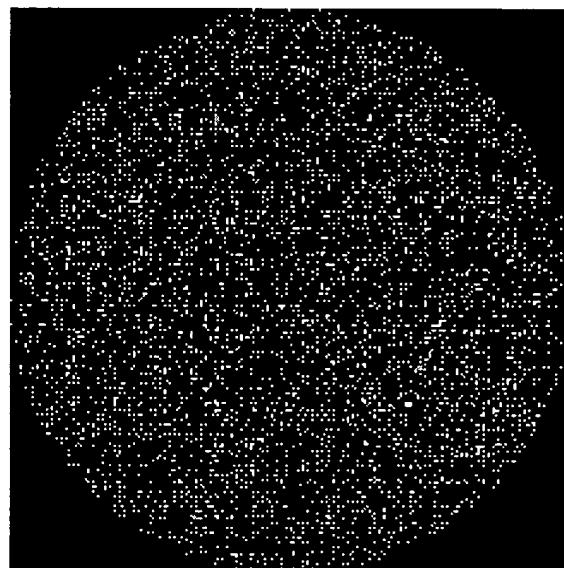


FIG. 23B

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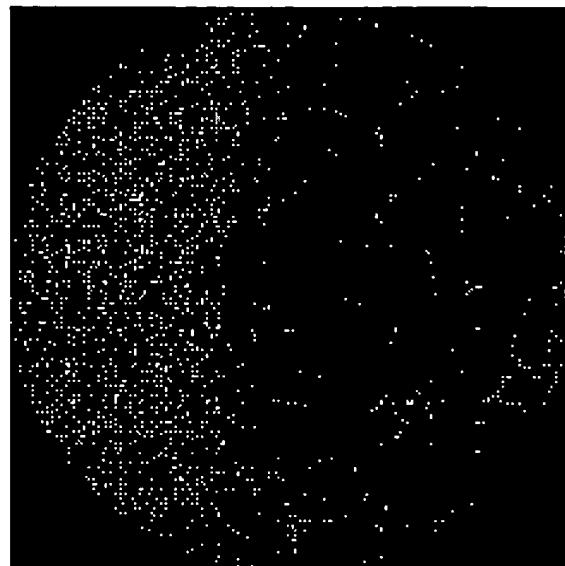


FIG. 23C

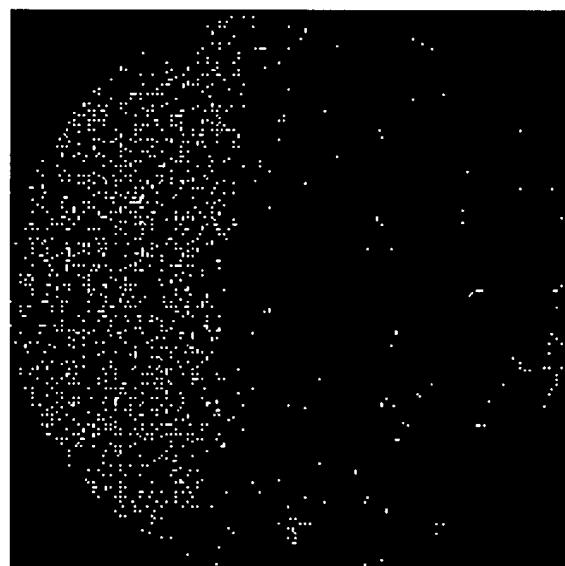


FIG. 23D

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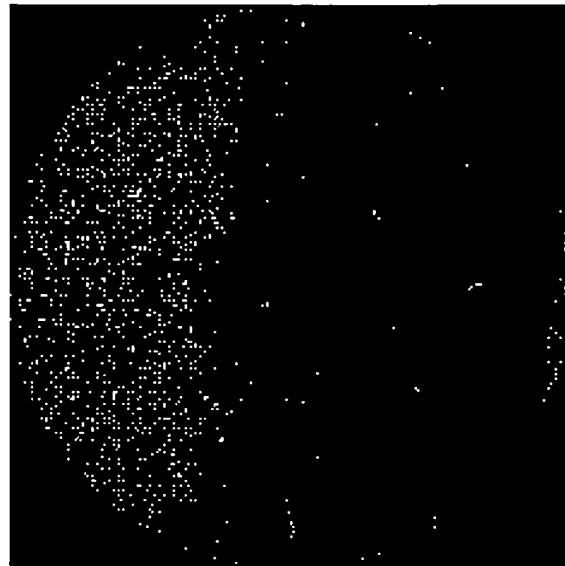


FIG. 23E

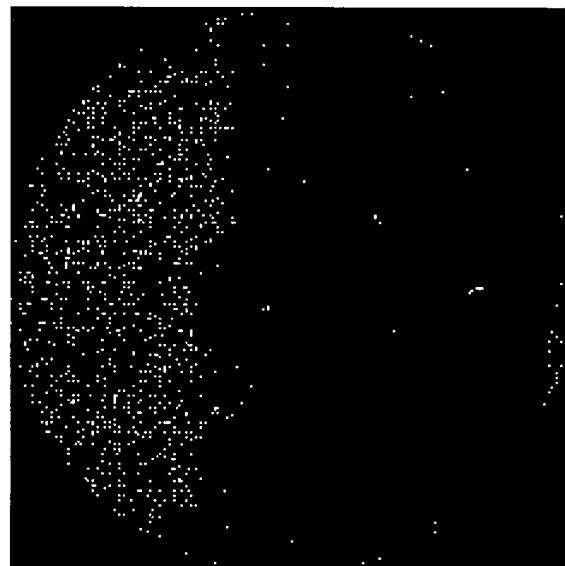


FIG. 23F

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